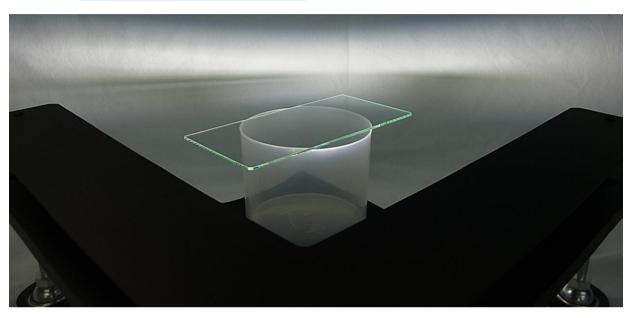
# For inspecting microscopic objects Low Angle illumination/LA-0

# Flett Power,

∼Reference exhibition∼



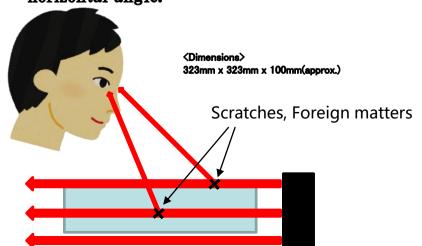
#### <Characteristics>

- · Method of ray control: Collimated
- · Work Distance: Variable
- · High sensitivity of detecting by using the dual angle irradiation.
- · Compatible for large work size.

## <Applications>

- Irradiating collimated ray from horizontal direction to transparent work generates variant rays on surface and inside of the work.
- · Convenient to detect microscopical matters at transparent works.

Drawing shown below explains how it works the illumination. Picture shown right is a sample of variant outcome from scratches irradiated from horizontal angle.





Observation of scratches

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Product specifications are subject to change without notice.